

#### 2N3946/FTSO3946 T-35-11

NPN Small Signal General Purpose Amplifier & Switch

V<sub>CEO</sub> ... 40 V (Min)

**PACKAGE** 

2N3946 FTSO3946 **TO18 TO236AA** 

ABSOLUTE MAXIMUM RATINGS (Note 1)

**FTSO 2N** Temperatures -65° C to 200° C -55° C to 150° C Storage Temperature 150° C 175° C Operating Junction Temperature

Power Dissipation (Notes 2 & 3)

**FTSO** 2N Total Dissipation at 0.350 W\* 0.36 mW 25° C Ambient Temperature 1,2 W 25° C Case Temperature

**Voltages & Currents** 

40 V V<sub>CEO</sub> Collector to Emitter Voltage 40 V (Note 4) 60 V 60 V Collector to Base Voltage V<sub>CBO</sub> 6.0 V 6.0 V V<sub>EBO</sub> Emitter to Base Voltage 200 mA 200 mA **Collector Current** 

ELECTRICAL CHARACTERISTICS (25° C Ambient Temperature unless otherwise noted) (Note 6)

	. CHARACTERISTICS (25° C Ambient Te	MIN	MAX	UNITS	TEST CONDITIONS
SYMBOL	CHARACTERISTIC		10077	V	$I_{C} = 10 \text{ mA}, I_{B} = 0$
BV <sub>CEO</sub>	Collector to Emitter Breakdown Voltage (Note 4)	40			
ВУсво	Collector to Base Breakdown Voltage	60		V	$I_{C} = 10 \ \mu\text{A}, \ I_{E} = 0$
	Emitter to Base Breakdown Voltage	6.0	1	٧	$I_E = 10 \ \mu A, \ I_C = 0$
BVEBO	Collector Cutoff Current		10	nA	$V_{CE} = 40 \text{ V}, V_{EB} = 3.0 \text{ V}$ $V_{CE} = 40 \text{ V}, V_{EB} = 3.0 \text{ V}, T_{A} = 150^{\circ}$
ICEX	Collegio: Cara	<u> </u>	15	μΑ	
	Base Cutoff Current	1	25	nA_	$V_{CE} = 40 \text{ V}, V_{EB} = 3.0 \text{ V}$
I <sub>BL</sub>		30			$I_{c} = 0.1 \text{ mA, } V_{ce} = 1.0 \text{ V}$
h <sub>FE</sub>	DC Current Gain (Note 5)	45			$I_{c} = 1.0 \text{ mA}, V_{ce} = 1.0 \text{ V}$
		50	150	1	$I_{C} = 10 \text{ mA}, V_{CE} = 1.0 \text{ V}$
		20	1		I <sub>C</sub> = 50 mA, V <sub>CE</sub> = 1.0 V
			<del> </del>	V V	I <sub>C</sub> = 10 mA, I <sub>B</sub> = 1.0 mA
V <sub>CE(sat)</sub>	Collector to Emitter Saturation	1	0.2	ľ	I <sub>C</sub> = 50 mA, I <sub>B</sub> = 5.0 mA
* CEISBU	Voltage (Note 5)		0.3	<u> </u>	
	Base to Emitter Saturation	0.6	0.9	V	I <sub>C</sub> = 10 mA, I <sub>B</sub> = 1.0 mA
V <sub>BE(sat)</sub>	Voltage (Note 5)	l	1.0	V	$I_{\rm C} = 50 \text{ mA}, I_{\rm B} = 5.0 \text{ mA}$

#### NOTES:

- These ratings are limiting values above which the serviceability of any individual semiconductor device may be impaired.

  These are steady state limits. The factory should be consulted on applications involving pulsed or low duty cycle operations.

  These ratings give a maximum junction temperature of 150°C and (TO-92) junction-to-case thermal resistance of 125°C/W (derating factor of 8.0 mW/°C); junction-to-ambient thermal resistance of 200° C/W (derating factor of 5.0 mW/°C); (TO-236) junction-to-ambient thermal resistance of 357° C/W (derating factor of 2.8 mW/° C).
- Rating refers to a high current point where collector to emitter voltage is lowest.
- Pulse conditions: length = 300  $\mu$ s; duty cycle = 2%.
- For product family characteristic curves, refer to Curve Set T144.
- Package mounted on 99.5% alumina 8 mm x 8 mm x 0.6 mm.

84D 27563

## 2N3946/FTSO3946

SYMBOL	CHARACTERISTIC	MIN	MAX	UNITS	TEST CONDITIONS
Соь	Output Capacitance		4.0	pF	V <sub>CB</sub> = 10 V, I <sub>E</sub> = 0, f = 100 kHz
Cib	Input Capacitance		8.0	pF	V <sub>EB</sub> = 1.0 V, I <sub>C</sub> = 0, f = 100 kHz
h <sub>fe</sub>	Current Gain Bandwidth Product	2.5			Ic = 10 mA, VcE = 20 V, f = 100 MHz
hie	Input Impedance	0.5	6.0	kΩ	Ic = 1.0 mA, VcE = 10 V, f = 1.0 kHz
h₀e	Output Admittance	1.0	30	μmhos	Ic = 1.0 mA, VcE = 10 V, f = 1.0 kHz
h <sub>re</sub>	Voltage Feedback Ratio		10	x10 <sup>-4</sup>	I <sub>C</sub> = 1.0 mA, V <sub>CE</sub> = 10 V, f = 1.0 kHz
ta	Delay Time (test circuit no. 526)		35	ns	$I_C = 10 \text{ mA}, V_{CC} = 3.0 \text{ V},$ $I_{B1} = 1.0 \text{ mA}, V_{BE(OFF)} = 0.5 \text{V}$
t <sub>r</sub>	Rise Time (test circuit no. 526)		300	ns	$I_C = 10 \text{ mA}, V_{CC} = 3.0 \text{ V},$ $I_{B1} = 1.0 \text{ mA}, V_{BE(OFF)} = 0.5 \text{V}$
t <sub>s</sub>	Storage Time (test circuit no. 527)		300	ns	$I_C = 10 \text{ mA}, V_{CC} = 3.0 \text{ V},$ $I_{B1} = I_{B2} = 1.0 \text{ mA}$
te	Fall Time (test circuit no. 527)		75	ns	I <sub>C</sub> = 10 mA, V <sub>CC</sub> = 3.0 V, I <sub>B1</sub> = I <sub>B2</sub> = 1.0 mA
rь′C₀	Collector to Base Time Constant		200	ps	$I_C = 10 \text{ mA}, V_{CE} = 20 \text{ V}, f = 31.8 \text{ MHz}$
NF	Noise Figure		5.0	dB	$I_C = 100 \mu A$ , $V_{CE} = 5.0 V$ , $R_G = 1.0 k\Omega$ , $f = 10 Hz$ to 15.7 kHz



# 2N3962/PN3962 T-29-23 **FTSO3962**

PNP Low Level Low Noise **Amplifiers** 

V<sub>CEO</sub> ... -60 V (Min)

Excellent Beta Linearity from 1.0  $\mu$ A to 50 mA

**PACKAGE** 

2N3962 PN3962 TO-18 TO-92

FTSO3962

TO-236AA/AB

## ABSOLUTE MAXIMUM RATINGS (Note 1)

PN/FTSO **Temperatures** -55°C to 150°C -65°C to 200°C Storage Temperature 175°C 150° C Operating Junction Temperature

Power Dissipation (Notes 2 & 3)

PN **FTSO** 2N Total Dissipation at 0.625 W 0.350 W\* 0.36 W 25° C Ambient Temperature 1.2 W 1.0 W 25° C Case Temperature

Voltages & Currents

-60 V V<sub>CEO</sub> Collector to Emitter Voltage (Note 4) -60 V V<sub>CBO</sub> Collector to Base Voltage V<sub>EBO</sub> Emitter to Base Voltage −6.0 V **Collector Current** 200 mA

# ELECTRICAL CHARACTERISTICS (25°C Ambient Temperature unless otherwise noted) (Note 6)

	CHARACTERISTIC	MIN	MAX	UNITS	TEST CONDITIONS
SYMBOL	Collector to Base Breakdown Voltage	-60		V	$I_{\rm C} = 10 \ \mu {\rm A}, \ I_{\rm E} = 0$
ВУсво			<del> </del>	v	$I_E = 10 \ \mu A, \ I_C = 0$
BVEBO	Emitter to Base Breakdown Voltage	6.0	<u> </u>	ļ <u>.</u>	
BV <sub>CES</sub>	Collector to Emitter Breakdown Voltage	-60			$I_{C} = 10 \ \mu A, \ I_{B} = 0$
lebo	Emitter Cutoff Current		10	nA	$V_{EB} = -4.0 \text{ V}, I_{C} = 0$
Ices	Collector Reverse Current		10 10	nA μA	$V_{CE} = -50 \text{ V}, V_{EB} = 0$ $V_{CE} = -50 \text{ V}, V_{EB} = 0, T_A = 150^{\circ} \text{ C}$
h <sub>FE</sub>	DC Current Gain	60 100 100 100 40	300 450 600		$\begin{array}{l} l_{C} = 1.0 \; \mu\text{A}, \; V_{CE} = -5.0 \; \text{V} \\ l_{C} = 10 \; \mu\text{A}, \; V_{CE} = -5.0 \; \text{V} \\ l_{C} = 100 \; \mu\text{A}, \; V_{CE} = -5.0 \; \text{V} \\ l_{C} = 1.0 \; \text{mA}, \; V_{CE} = -5.0 \; \text{V} \\ l_{C} = 1.0 \; \mu\text{A}, \; V_{CE} = -5.0 \; \text{V}, \; T_{A} = -55 ^{\circ}\text{C} \\ l_{C} = 1.0 \; \text{mA}, \; V_{CE} = -5.0 \; \text{V}, \; T_{A} = 100 ^{\circ}\text{C} \end{array}$

#### NOTES:

These ratings are limiting values above which the serviceability of any individual semiconductor device may be impaired.

These are steady state limits. The factory should be consulted on applications involving pulsed or low duty cycle operations.

These ratings give a maximum junction temperature of 150°C and (TO-92) junction-to-case thermal resistance of 125°C/W (derating factor of 8.0 mW/°C); junction-to-ambient thermal resistance of 200° C/W (derating factor of 5.0 mW/°C); (TO-236) junction-to-ambient thermal resistance of 357° C/W (derating factor of 2.8 mW/°C).

Rating refers to a high current point where collector to emitter voltage is lowest. Pulse conditions: length = 300  $\mu$ s; duty cycle = 1%.

For product family characteristic curves, refer to Curve Set T219.

Package mounted on 99.5% alumina 8 mm x 8 mm x 0.6 mm.

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#### 2N3962/PN3962/FTSO3962

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SYMBOL	CHARACTERISTIC	MIN	MAX	UNITS	TEST CONDITIONS
h <sub>FE</sub>	DC Pulse Current Gain (Note 5)	100 90 45			$\begin{array}{l} I_{C} = 10 \text{ mA, } V_{CE} = -5.0 \text{ V} \\ I_{C} = 50 \text{ mA, } V_{CE} = -5.0 \text{ V} \\ I_{C} = 50 \text{ mA, } V_{CE} = -5.0 \text{ V, } T_{A} = -55^{\circ} \text{ C} \end{array}$
V <sub>CE(sat)</sub>	Collector to Emitter Saturation Voltage Collector to Emitter Saturation Voltage (Note 5)		-0.25 -0.4	V V	$I_C$ = 10 mA, $I_B$ = 0.5 mA $I_C$ = 50 mA, $I_B$ = 5.0 mA
V <sub>BE(sat)</sub> V <sub>BE(sat)</sub>	Base to Emitter Saturation Voltage Base to Emitter Saturation Voltage (Note 5)		−0.9 −0.95	V V	$I_C = 10$ mA, $I_B = 0.5$ mA $I_C = 50$ mA, $I_B = 5.0$ mA
V <sub>CEO(sus)</sub>	Collector to Emitter Sustaining Voltage (Notes 4 & 5)		-60	٧	I <sub>C</sub> = 5.0 mA, I <sub>B</sub> = 0
Соь	Open Circuit Output Capacitance		6.0	pF	$V_{CB} = -5.0 \text{ V}, I_E = 0, f = 1.0 \text{ MHz}$
Cib	Open Circuit Input Capacitance		15	pF	$V_{EB} = -5.0 \text{ V}, I_C = 0, f = 1.0 \text{ MHz}$
h <sub>fe</sub>	High Frequency Current Gain	2.0	8.0		$I_C = 0.5 \text{ mA}, V_{CE} = -5.0 \text{ V}, f = 20 \text{ MHz}$
h <sub>fe</sub>	Small Signal Current Gain	100	500		$I_C = 1.0 \text{ mA}, V_{CE} = -5.0 \text{ V}, f = 1.0 \text{ kHz}$
h <sub>ie</sub>	Input Resistance	2.5	17	kΩ	$I_C = 1.0 \text{ mA}$ , $V_{CE} = 5.0 \text{ V}$ , $f = 1.0 \text{ kHz}$
hoe	Output Conductance	5.0	40	μmhos	$I_C = 1.0 \text{ mA}, V_{CE} = -5.0 \text{ V}, f = 1.0 \text{ kHz}$
h <sub>re</sub>	Voltage Feedback Ratio		10	x10⁻⁴	$I_C = 1.0 \text{ mA}, V_{CE} = -5.0 \text{ V}, f = 1.0 \text{ kHz}$
NF	Wide Band Noise Figure		3.0	dB	$I_{C} = 20~\mu\text{A}$ , $V_{CE} = -5.0~\text{V}$ , $R_{S} = 10~\text{k}\Omega$ , BW = 15.7 Hz, f = 10 Hz to 10 kHz



T-29-17

## 3469674 FAIRCHILD SEMICONDUCTOR

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2N4030/2N4031 2N4032/2N4033

PNP Small Signal General Purpose **Amplifiers** 

V<sub>CEO</sub> ... 60 V (Min) (2N4030/2), 80 V (Min) 2N4031/3)

h<sub>FE</sub> ... 100-300 @ 10 mA (2N4032/3), 40 (Min) 2N4032),

25 (Min) (2N4033) @ 1.0 A Complements ... 2N3107, 2N3108, 2N3109, 2N3020 **PACKAGES** 

2N4030 TO-39 TO-39 2N4031

TO-39 2N4032 TO-39 2N4033

## **ABSOLUTE MAXIMUM RATINGS** (Note 1)

**Temperatures** 

Storage Temperature -65° C to 200° C 200° C Operating Junction Temperature

Power Dissipation (Notes 2 & 3)

Total Dissipation at

0.8 W 25° C Ambient Temperature 4.0 W 25° C Case Temperature

4030/2 4031/3 Voltages & Currents -60 V -80 V V<sub>CEO</sub> Collector to Emitter Voltage

(Note 4) -60 V V<sub>CBO</sub> Collector to Base Voltage

-80 V -5.0 V -5.0 V V<sub>EBO</sub> Emitter to Base Voltage 1.0 A **Collector Current** 1.0 A

# ELECTRICAL CHARACTERISTICS (25° C Ambient Temperature unless otherwise noted) (Note 6)

SYMBOL	CHARACTERISTIC	40 MIN	30 MAX	40 MIN	31 MAX	UNITS	TEST CONDITIONS
ВУсво	Collector to Base Breakdown Voltage	60		-80		V	$I_{C} = 10 \ \mu A, \ I_{E} = 0$
BV <sub>EBO</sub>	Emitter to Base Breakdown Voltage	-5.0		<del>-</del> 5.0		V	$I_E = 10 \ \mu A, I_C = 0$
I <sub>EBO</sub>	Emitter Cutoff Current		10		10	μΑ	$V_{EB} = -5.0 \text{ V}, I_{C} = 0$
Ісво	Collector Cutoff Current		50 50		50 50	nA nA μA	$\begin{array}{l} V_{CB} = -50 \text{ V},  I_E = 0 \\ V_{CB} = -60 \text{ V},  I_E = 0 \\ V_{CB} = -50 \text{ V},  I_E = 0, \\ T_A = 150^{\circ} \text{ C} \\ V_{CB} = -60 \text{ V},  I_E = 0, \end{array}$
h <sub>FE</sub>	DC Current Gain	30		30			$T_A = 150^{\circ} \text{ C}$ $I_C = 100 \ \mu\text{A}, \ V_{CE} = -5.0 \ \text{V}$

#### NOTES:

- These ratings are limiting values above which the serviceability of any individual semiconductor device may be impaired.
- These are steady state limits. The factory should be consulted on applications involving pulsed or low duty cycle operations.
- These ratings give a maximum junction temperature of 200° C and junction-to-case thermal resistance of 43.7° C/W (derating factor of 22.8 mW/° C); junction-to-ambient thermal resistance of 219° C/W (derating factor of 4.56 mW/° C).
- Rating refers to a high current point where collector to emitter voltage is lowest.
- Pulse conditions: length = 300 us; duty cycle = 1%.
- For product family characteristic curves, refer to Curve Set T224.

VCEO

Collector to Emitter Sustaining

Voltage (Note 5)

## 3469674 FAIRCHILD SEMICONDUCTOR

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2N4030/2N4031 2N4032/2N4033

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 $I_C = 10 \text{ mA (pulsed)}, I_B = 0$ 

LECTRICA	L CHARACTERISTICS (05° C A	biont 7	Fo		-10-0-04		atad) (Nata O)
LECTRICA	L CHARACTERISTICS (25° C Am	<del>, , , , , , , , , , , , , , , , , , , </del>				nerwise n	oted) (Note 6)
SYMBOL	CHARACTERISTIC	MIN	030 MAX	MIN	D31 MAX	UNITS	TEST CONDITIONS
h <sub>FE</sub>	DC Pulse Current Gain (Note 5)	40 25 15 15	120	40 25 10 15	120		$ \begin{array}{l} I_{C} = 100 \text{ mA}, \ V_{CE} = -5.0 \ V \\ I_{C} = 500 \text{ mA}, \ V_{CE} = -5.0 \ V \\ I_{C} = 1.0 \ A, \ V_{CE} = -5.0 \ V \\ I_{C} = 100 \ \text{mA}, \ V_{CE} = -5.0 \ V, \\ T_{A} = -55^{\circ} \ C \\ \end{array} $
Vceo	Collector to Emitter Sustaining Voltage (Note 5)	-60		80		٧	$I_C = 10$ mA (pulsed), $I_B = 0$
V <sub>CE(sat)</sub>	Collector to Emitter Saturation Voltage (Note 5)		-0.15 -0.5  1.0		−0.15 −0.5	V V V	l <sub>C</sub> = 150 mA, l <sub>B</sub> = 15 mA l <sub>C</sub> = 500 mA, l <sub>B</sub> = 50 mA l <sub>C</sub> = 1.0 A, l <sub>B</sub> = 100 mA
V <sub>BE(ON)</sub>	Base to Emitter "On" Voltage (Note 5)		-1.1 -1.2		-1.1	V	$I_{C} = 500 \text{ mA}, V_{CE} = -0.5 \text{ V}$ $I_{C} = 1.0 \text{ A}, V_{CE} = -1.0 \text{ V}$
V <sub>BE(sat)</sub>	Base to Emitter Saturation Voltage (Note 5)		-0.9		-0.9	٧	I <sub>C</sub> = 150 mA, I <sub>B</sub> = 15 mA
Ссь	Collector to Base Capacitance		20		20	pF	$V_{CB} = -10 \text{ V}, I_E = 0, f = 1.0 \text{ MHz}$
Cib	Input Capacitance		110		110	рF	$V_{BE} = -0.5 \text{ V}, I_{C} = 0, f = 1.0 \text{ MHz}$
h <sub>fe</sub>	Magnitude of Common Emitter Small Signal Current Gain	1.0	4.0	1.0	4.0	-	$I_C = 50 \text{ mA}, V_{CE} = -10 \text{ V},$ f = 100 MHz
t <sub>s</sub>	Storage Time (test circuit no. 341)		350		350	ns	$I_{\rm C} \approx 500 \mathrm{mA}$ , $I_{\rm B1} \approx -I_{\rm B2} \approx 50 \mathrm{mA}$
tı	Fall Time (test circuit no. 341)		50		50	ns	I <sub>C</sub> ≈500 mA, I <sub>B1</sub> ≈−I <sub>B2</sub> ≈50 mA
ton	Turn On Time (test circuit no. 341)		100		100	ns	$I_{C} \approx 500$ mA, $I_{B1} \approx 50$ mA
				,			
SYMBOL	CHARACTERISTIC	40 MIN	32 MAX	40 MIN	033 MAX	UNITS	TEST CONDITIONS
ВУсво	Collector to Base Breakdown Voltage	-60		-80		٧	$I_{C} = 10 \ \mu A, \ I_{E} = 0$
BV <sub>EBO</sub>	Emitter to Base Breakdown Voltage	-5.0		-5.0		٧	$I_E = 10 \ \mu A, \ I_C = 0$
I <sub>EBO</sub>	Emitter Cutoff Current		10		10	μΑ	$V_{EB} = -5.0 \text{ V, } I_{C} = 0$
Ісво	Collector Cutoff Current		50 50		50 50	nA nA μA μA	$V_{CB} = -50 \text{ V}, I_E = 0$ $V_{CB} = -60 \text{ V}, I_E = 0$ $V_{CB} = -50 \text{ V}, I_E = 0, T_A = 150^{\circ} \text{ C}$ $V_{CB} = -60 \text{ V}, I_E = 0, T_A = 150^{\circ} \text{ C}$
h <sub>FE</sub>	DC Current Gain	75		75			$I_C = 100 \mu A, V_{CE} = -5.0 \text{ V}$
h <sub>FE</sub>	DC Pulse Current Gain (Note 5)	100 70 40 40	300	100 70 25 40	300		$ \begin{array}{l} I_{C} = 100 \text{ mA, } V_{CE} = -5.0 \text{ V} \\ I_{C} = 500 \text{ mA, } V_{CE} = -5.0 \text{ V} \\ I_{C} = 1.0 \text{ A, } V_{CE} = -5.0 \text{ V} \\ I_{C} = 100 \text{ mA, } V_{CE} = -5.0 \text{ V, } \\ T_{A} = -55^{\circ} \text{ C} \\ \end{array} $
11	0 11 1 7 11 0 1 1 1						



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2N4030/2N4031 2N4032/2N4033

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		40	32	40	033		
SYMBOL	CHARACTERISTIC	MIN	MAX	MIN	MAX	UNITS	TEST CONDITIONS
VCE(sat)	Collector to Emitter Saturation Voltage (Note 5)		-0.15 -0.5		-0.15 -0.5 -1.0	V V	$I_C = 150$ mA, $I_B = 15$ mA $I_C = 500$ mA, $I_B = 50$ mA $I_C = 1.0$ A, $I_B = 100$ mA
V <sub>BE(ON)</sub>	Base to Emitter "On" Voltage (Note 5)		-1.1  1.2		-1.1	V V	$I_C = 500$ mA, $V_{CE} = -0.5$ V $I_C = 1.0$ A, $V_{CE} = -1.0$ V
V <sub>BE(sat)</sub>	Base to Emitter Saturation Voltage (Note 5)		-0.9		-0.9	٧	I <sub>C</sub> = 150 mA, I <sub>B</sub> = 15 mA
Ссь	Collector to Base Capacitance		20		20	pF	$V_{CB} = -10 \text{ V}, I_E = 0, f = 1.0 \text{ MHz}$
Сіь	Input Capacitance		110		110	pF	$V_{BE} = -0.5 \text{ V}, I_{C} = 0, f = 1.0 \text{ MHz}$
h <sub>fe</sub>	Magnitude of Common Emitter Small Signal Current Gain	1,5	5.0	1.5	5.0		$I_C = 50 \text{ mA}, V_{CE} = -10 \text{ V},$ f = 100 MHz
t <sub>s</sub>	Storage Time (test circuit no. 341)		350		350	ns	$I_C \approx 500 \text{ mA}, I_{B1} \approx I_{B2} \approx 50 \text{ mA}$
tr	Fall Time (test circuit no. 341)		50		50	ns	$I_C \approx 500 \text{ mA}, I_{B1} \approx I_{B2} \approx 50 \text{ mA}$
t <sub>on</sub>	Turn On Time (see test circuit no. 341)		100		100	ns	$I_{C} \approx 500$ mA, $I_{B1} \approx 50$ mA

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#### 2N4036/2N4037

T-27-23

PNP General Purpose Transistor

**ABSOLUTE MAXIMUM RATINGS (Note 1)** 

**PACKAGE** 

2N4036 2N4037

TO-39 TO-39

**Temperatures** 

-65° C to 200° C

Storage Temperature Operating Junction Temperature -65°C to 200°C

Power Dissipation (Notes 2 & 3) Total Dissipation at

25° C Ambient Temperature

4036 4037 5.0 W 1.0 W

Voltages & Currents (Note 4) 4036

4037 V<sub>CEO</sub> Collector to Emitter Voltage -65 V -40 V V<sub>CBO</sub> Collector to Base Voltage -90 V -60 V V<sub>EBO</sub> Emitter to Base Voltage −7.0 V −7.0 V

Collector Current (Continuous) 1.0 A 1.0 A Base Current (Continuous) 0.5 A 0.5 A

ELECTRICAL CHARACTERISTICS (25°C Ambient Temperature unless otherwise noted) (Note 6)

SYMBOL	CHARACTERISTIC	2N4 MIN	4036 MAX	2N4 MIN	1037 MAX	UNITS	TEST CONDITIONS
BVCEO	Collector to Emitter Sustaining Voltage	-65	IVIAA	-40	IWIAA	V	I <sub>C</sub> = 100 mA, I <sub>B</sub> = 0
ВVсво	Collector to Base Breakdown Voltage			-60		V	I <sub>C</sub> = 0.1 mA
I <sub>EBO</sub>	Emitter Cutoff Current		10		1.0	μΑ μΑ	V <sub>EB</sub> = -7.0 V V <sub>EB</sub> = -5.0 V
Ісво	Collector Cutoff Current		100		0.25	μA μA	$V_{CB} = -90 \text{ V, } I_E = 0$ $V_{CB} = -60 \text{ V, } I_E = 0$
I <sub>CEX</sub>	Collector Cutoff Current		100 0.1			mA μA	$V_{CE} = -85 \text{ V}, V_{BE} = -1.5 \text{ V}$ $V_{CE} = -30 \text{ V}, V_{BE} = -1.5 \text{ V}$ $T_{C} = 150^{\circ} \text{ C}$
h <sub>FE</sub>	DC Current Gain (Note 5)	20 20 40 20	200 140	15 50	250		$\begin{array}{c} I_{C} = 150 \text{ mA}, \ V_{CE} = 2.0 \ V \\ I_{C} = 100 \ \mu\text{A}, \ V_{CE} = 10 \ V \\ I_{C} = 1.0 \ \text{mA}, \ V_{CE} = 10 \ V \\ I_{C} = 150 \ \text{mA}, \ V_{CE} = 10 \ V \\ I_{C} = 500 \ \text{mA}, \ V_{CE} = 10 \ V \end{array}$
V <sub>CE(sat)</sub>	Collector to Emitter Saturation Voltage		-0.65		-1.4	٧	I <sub>C</sub> = 150 mA, I <sub>B</sub> = 15 mA
V <sub>BE(sat)</sub>	Base to Emitter Saturation Voltage (Note 5)		-1.4			٧	I <sub>C</sub> = 150 mA, I <sub>B</sub> = 15 mA
V <sub>BE(ON)</sub>	Base to Emitter On Voltage			-1.4		٧	$I_{C} = 150 \text{ mA}, V_{CE} = 10 \text{ V}$

#### NOTES:

- These ratings are limiting values above which the serviceability of any individual semiconductor device may be impaired.
- These are steady state limits. The factory should be consulted on applications involving pulsed or low duty cycle operations.

  These ratings give a maximum junction temperature of 200° C and (2N4036) junction-to-case thermal resistance of 35° C/W (derating factor of 28.6 mW/° C); (2N4037) junction-to-case thermal resistance of 175° C/W (derating factor of 5.71 mW/° C).
- Rating refers to a high current point where collector to emitter voltage is lowest.
- Pulse conditions: length = 300 μs, duty cycle = 1%.
- For product family characteristic curves, refer to Curve Set T224.



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		2N4	1036	2N4	4037		
SYMBOL	CHARACTERISTIC	MIN	MAX	MIN	MAX	UNITS	TEST CONDITIONS
h <sub>fe</sub>	High Frequency Current Gain	3.0		3.0	10		$I_C = 50 \text{ mA}, V_{CE} = -10 \text{ V},$ f = 20 MHz
Ccb	Collector to Base Capacitance				30	pF	V <sub>CB</sub> = 10 V, f = 1.0 MHz
t <sub>r</sub>	Rise Time		70			ns	I <sub>C</sub> = 150 mA, I <sub>B1</sub> = 15 mA
ts	Storage Time		600			ns	$I_C = 150 \text{ mA}, I_{B1} = I_{B2} = 15 \text{ mA}$
t <sub>f</sub>	Fall Time		100			ns	$I_C = 150 \text{ mA}, I_{B1} = I_{B2} = 15 \text{ mA}$
ton	Turn On Time		110			ns	I <sub>C</sub> = 150 mA, I <sub>B1</sub> = 15 mA
toff	Turn Off Time		700			ns	$I_C = 150 \text{ mA}, I_{B1} = I_{B2} = 15 \text{ mA}$